FORM PTO-1449

US DEPARTMENT OF COMMERCE
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Applicant: Barry D. Silverstein, et al

LIST OF ART CITED BY APPLICANT

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Herewith 03/30/2004

^{Group} 237 To be Assigned

	(Use several skeets	if necessary)	Herewith 03/30/2009			To be Assigned	
			U.S. PATENT DOCUMENTS				
Examiner Initial*	DOCUMENT NUMBER	DATE	NAME	(LV22	SUBCLASS	FILING DATE IF APPROPRIATE	
T-R-CI	4,441,791	4/10/84	Hornbeck	359	295		
	5,535,047	7/9/96	Hornbeck	359	295		
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	5,719,695	2/17/98	Heimbuch	359	291		
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	5,930,050	7/27/99	Dewald	359	670		
	6,008,951	12/28/99	Anderson	359	677		
	6,089,717	7/18/00	Iwai	353	31		
	5,808,795	9/15/98	Shimomura et al.	359	488		
	5,798,819	8/25/98	Hattori et al.	353	33		
	5,918,961	7/6/99	Ueda	353	20		
	6,010,121	1/4/00	Lee	269	94		
	6,062,694	5/16/00	Oikawa et al.	353	31		
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	5,978,056	11/2/99	Shintani et al.	349	137"		
	5,620,755	4/15/97	Smith, Jr. et al.	428	1.21		
	2,403,731	7/9/46	MacNeille	359	438		
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	5,844,722	12/1/98	Stephens et al.	359	637		
	5,383,053	1/17/95	Hegg et al.	359	456		
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Examiner Initial*	DOCUMENT NUMBER	DATE	COUNTRY .	CLASS	SUBCLASS	TRANSLATION YES I NO				
initial		OTHER ART (Inch	ding Author, Title. Date, Pertinent Pages,	Etc.)						
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*EXAMINER	*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with meet communication to applicant.									